

Why wait  
for Sample  
Prep!

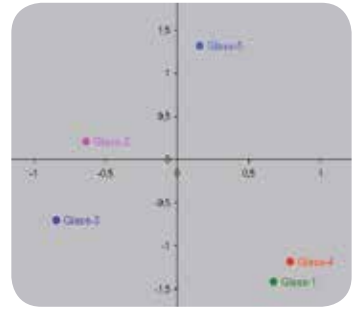
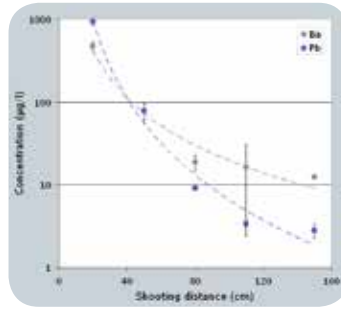
• **S2 PICOFOX** TXRF Spectrometer

Benchtop TXRF for Ultra Low Detection Limits

- Fast sample preparation without digestion
- Concentrations from 0.1 ppb to 100 percent
- Sample amounts down to nanograms
- No consumables, gases or cooling water

**Solutions for Forensic Scientists ...**





### Forensic Distance Determination after Firearm use

Total reflection X-Ray Fluorescence (TXRF) offers simultaneous trace element analysis of gunshot residues for distance determination.

- The TXRF spectrometer S2 PICOFOX is suitable for distance determination after firearm shooting
- TXRF supports simultaneous element analysis, also in case of unknown ammunition
- TXRF is not affected by colours (tissues, blood)
- TXRF provides the flexibility to deal with future changes of primer compositions

### Characterization and correspondence analysis of glass fragments

Total reflection X-Ray Fluorescence requires only smallest sample amounts and allows non-destructive analysis of glass splinters.

- The TXRF spectrometer S2 PICOFOX is suitable for the accurate elemental analysis of glass fragments
- A simple semi-quantitative procedure supports fast characterization of glass types
- Correspondence analysis allows identification of glass manufacturers

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